Chip Monolithic Ceramic Capacitor for Automotive GCM2195G1H911JA16_ (0805, X8G:EIA, 910pF, DC50V)

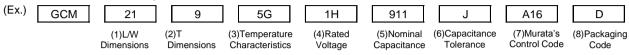
_: packaging code

Reference Sheet

1.Scope

This product specification is applied to Chip Monolithic Ceramic Capacitor used for Automotive Electronic equipment.

2.MURATA Part NO. System



3. Type & Dimensions



(Unit:mn						
(1)-1 L	(1)-2 W	(2) T	e	g		
2.0±0.15	1.25±0.15	0.85±0.1	0.2 to 0.7	0.7 min.		

4.Rated value

	e Characteristics ode):X8G(EIA)	(4) Rated	(5) Nominal	(6) Capacitance	Specifications and Test Methods
Temp. coeff or Cap. Change	Temp. Range (Ref.Temp.)	Voltage	Capacitance	Tolerance	(Operating Temp. Range)
0±30 ppm/°C	25 to 150 °C (25 °C)	DC 50 V	910 pF	±5 %	-55 to 150 °C

5.Package

mark	(8) Packaging	Packaging Unit
D	∳180mm Reel PAPER W8P4	4000 pcs./Reel
J	∳330mm Reel PAPER W8P4	10000 pcs./Reel

Product specifications in this catalog are as of Oct.13,2015,and are subject to change or obsolescence without notice. Please consult the approval sheet before ordering. Please read rating and !Cautions first.

■AEC-Q200 Murata Standard Specification and Test Methods

				ecification.				AEO 0000 T M	
٩N	AEC-Q20	0 Test Item	Temperature Compensating Type	High Dielectric Type				AEC-Q200 Test Meth	100
1	Pre-and Po			<u> </u>					
<u>,</u>	Electrical Te		<u>-</u>		-				0-
2	High Tempe		The measured and observed chara	cteristics should satisfy the				00±12 hours at 150±3	
	Exposure (S		specifications in the following table.		Se	t for 24:	E2 nours at ro	om temperature, then	measure.
		Appearance Capacitance	No marking defects Within ±2.5% or ±0.25pF	R7/L8/R9 : Within ±10.0%	-				
				R7/L0/R9 : Within ±10.0%					
		Change Q/D.F.	(Whichever is larger) 30pFmin. : Q≧1000	R7/L8 W.V.: 25Vmin. : 0.03 max.					
		Q/D.F.	30pFmax.: Q ≧400+20C	W.V.: 16V/10V : 0.05 max.					
			C: Nominal Capacitance(pF)	R9 : 0.075max.					
			o. Norminal Capacitance(pr)						
		I.R.		Ω or 500 $\Omega \cdot F(Whichever is smaller)$					
			R9 : More than 3000MΩ or 150Ω •F	F(Whichever is smaller)					
3	Temperatur	e Cycling	The measured and observed chara	cteristics should satisfy the	Fix	the cap	acitor to the	supporting jig in the sa	ame manner and under
			specifications in the following table.			e same (conditions as	(19). Perform cycle te	st according to the fou
		Appearance	No marking defects		hea	at treatr	nents listed in	the following table. S	et for 24±2 hours at
		Capacitance	Within ±2.5% or ±0.25pF	R7/L8/R9: Within ±10.0%	roc	om temp	perature, then	measure	
		Change	(Whichever is larger)			<u></u>	T · /··	Cvc	les
		Q/D.F.	30pFmin. : Q≧1000	R7/L8 W.V.: 25Vmin. : 0.03 max. *	l	Step	Time(min)	1000 (for ∆C/R7)	300(for 5G/L8/R9)
			30pFmax.: Q ≧400+20C	* GCM188R7 1E/1H 563 to 104:0.05 max		1	15±3	-55°C+0/-3	-55°C+0/-3
			C: Nominal Capacitance(pF)	W.V.: 16V/10V : 0.05 max.		2	1	Room	Room
				R9 : 0.05max.		3	15±3	125°C+3/-0	150°C+3/-0
		I.R.	More than $10,000M\Omega$ or $500\Omega \cdot F$			4	1	Room	Room
			(Whichever is smaller)						
								r high dielectric const	
									one hour and then set
							ours at room		
					Pe	nonn u	e initial meas	urement.	
4	Destructive		No defects or abnormalities		Pe	r EIA-46	69.		
	Physical An	alysis							
		alysis	The measured and observed chara	cteristics should satisfy the	Ap	ply the 2	24-hour heat (25 to 65°C) and humic	
	Physical An	alysis esistance	The measured and observed chara specifications in the following table.	cteristics should satisfy the	Ap tre	ply the 2 atment	24-hour heat (shown below,	10 consecutive times	
	Physical An	alysis esistance Appearance	The measured and observed chara specifications in the following table. No marking defects		Ap tre	ply the 2 atment	24-hour heat (shown below, ±2 hours at r	10 consecutive times oom temperature, the	
	Physical An	alysis esistance Appearance Capacitance	The measured and observed chara specifications in the following table. No marking defects Within ±3.0% or ±0.30pF	R7/L8/R9 : Within ±12.5% Temp	Ap trea Se	ply the 2 atment t for 24	24-hour heat (shown below, ±2 hours at r	10 consecutive times com temperature, the	n measure. idity
	Physical An	Appearance Capacitance Change	The measured and observed chara specifications in the following table. No marking defects Within ±3.0% or ±0.30pF (Whichever is larger)	R7/L8/R9 : Within ±12.5% Temp (%	Ap trea Se	ply the 2 atment t for 24	24-hour heat (shown below, ±2 hours at r	10 consecutive times noom temperature, the humidity Humi	n measure.
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5	Physical An Moisture Re	Appearance Capacitance Change Q/D.F. I.R. I.R.	The measured and observed chara specifications in the following table. No marking defects Within $\pm 3.0\%$ or ± 0.30 pF (Whichever is larger) 30 pFmin. : Q ≥ 350 10 pF and over, 30 pF and below: $Q \ge 275+5C/2$ 10 pFmax.: Q $\ge 200+10$ C C: Nominal Capacitance(pF) 5C/5G/R7/L8 : More than $10,000$ MG R9 : More than 3000 MΩ or 150Ω · f $R9$: More than 3000 MΩ or 150Ω · f The measured and observed chara specifications in the following table. No marking defects Within $\pm 3.0\%$ or ± 0.30 pF	R7/L8/R9 : Within ±12.5% Temp (% R7/L8 : W.V.: 35Vmin.: 0.03 max. 6 W.V.: 25Vmax. : 0.05 max. 6 R9 : 0.075max. 4 30 or 500Ω •F(Whichever is smaller) 2 =(Whichever is smaller) 1 = 1 cteristics should satisfy the	Ap treation See ration 55 55 55 55 55 55 55 55 55 55 55 55 55	ply the 2 atment t for 24: ure	24-hour heat (shown below, ±2 hours at r Humidity 90-98% + Humidity 90 + Humidity 90 + Humidity 90% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity + Humidity 100% + Humidity + Humid	10 consecutive times com temperature, the 10 − 98% Humidity 80- 90 − 98% 40 10 − 10 − 10 10 − 10 1	h measure. idity 90~98% 90~98% 10 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1
5	Physical An Moisture Re	Appearance Capacitance Change Q/D.F. I.R. I.R.	The measured and observed chara specifications in the following table. No marking defects Within $\pm 3.0\%$ or ± 0.30 pF (Whichever is larger) 30 pFmin. : Q ≥ 350 10 pF and over, 30 pF and below: $Q \ge 275+5C/2$ 10 pFmax.: Q $\ge 200+10$ C C: Nominal Capacitance(pF) 5C/5G/R7/L8 : More than $10,000$ M R9 : More than 3000 MΩ or 150 Ω · f 9 : More than 3000 MΩ or 150 Ω · f The measured and observed chara specifications in the following table. No marking defects Within $\pm 3.0\%$ or ± 0.30 pF (Whichever is larger)	R7/L8/R9 : Within ±12.5% Temp (% R7/L8 : W.V.: 35Vmin.: 0.03 max. 6 W.V.: 25Vmax. : 0.05 max. 6 R9 : 0.075max. 6 Q or 500Q •F(Whichever is smaller) 2 E(Whichever is smaller) 1 C or 500Q •F(Whichever is smaller) 2 E(Whichever is smaller) 1 E(Whichever is smaller) 1 E(Whichever is smaller) 1 R7/L8/R9: Within ±12.5% 1	Ap treation See ration 55 55 55 55 55 55 55 55 55 55 55 55 55	ply the 2 atment t for 24: ure	24-hour heat (shown below, ±2 hours at r Humidity 90-98% + Humidity 90 + Humidity 90 + Humidity 90% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity + Humidity 100% + Humidity + Humid	10 consecutive times com temperature, the 10 − 98% Humidity 80- 90 − 98% 40 10 − 10 − 10 10 − 10 1	h measure. idity 90~98% 90~98% 10 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1
5	Physical An Moisture Re	Appearance Capacitance Change Q/D.F. I.R. I.R.	The measured and observed chara specifications in the following table. No marking defects Within $\pm 3.0\%$ or ± 0.30 pF (Whichever is larger) 30 pFmin. : Q ≥ 350 10 pF and over, 30 pF and below: $Q \ge 275+5C/2$ 10 pFmax.: Q $\ge 200+10C$ C: Nominal Capacitance(pF) 5C/5G/R7/L8 : More than $10,000$ M R9 : More than 3000 MΩ or 150Ω · f $R9$: More than 3000 MΩ or 150Ω · f The measured and observed chara specifications in the following table. No marking defects Within $\pm 3.0\%$ or ± 0.30 pF (Whichever is larger) 30 pF and over: Q ≥ 200	R7/L8/R9 : Within ±12.5% Temp (% R7/L8 : W.V.: 35Vmin.: 0.03 max. 6 W.V.: 25Vmax. : 0.05 max. 6 R9 : 0.075max. 6 Q or 500Q •F(Whichever is smaller) 2 F(Whichever is smaller) 2 F(Whichever is smaller) 1 Temp 1 Temp 1 R7/L8/R9: Within ±12.5% 7 R7/L8 W.V.: 35Vmin.: 0.035 max.*	Ap treation See ration 55 55 55 55 55 55 55 55 55 55 55 55 55	ply the 2 atment t for 24: ure	24-hour heat (shown below, ±2 hours at r Humidity 90-98% + Humidity 90 + Humidity 90 + Humidity 90% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity + Humidity 100% + Humidity + Humid	10 consecutive times com temperature, the 10 − 98% Humidity 80- 90 − 98% 40 10 − 10 − 10 10 − 10 1	h measure. idity 90~98% 90~98% 10 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1
5	Physical An Moisture Re	Appearance Capacitance Change Q/D.F. I.R. I.R.	The measured and observed chara specifications in the following table. No marking defects Within $\pm 3.0\%$ or ± 0.30 pF (Whichever is larger) 30 pFmin. : Q ≥ 350 10 pF and over, 30 pF and below: $Q \ge 275+5C/2$ 10 pFmax.: Q $\ge 200+10C$ C: Nominal Capacitance(pF) 5C/5G/R7/L8 : More than $10,000$ M2 R9 : More than 3000 MΩ or 150Ω · f P = More than 3000 MΩ or 150Ω · f Whichever than 3000 MΩ or 150Ω · f Within $\pm 3.0\%$ or ± 0.30 pF (Whichever is larger) 30 pF and over: Q ≥ 200 30 pF and below: Q $\ge 100+10C/3$	R7/L8/R9 : Within ±12.5% Temp (% R7/L8 : W.V.: 35Vmin.: 0.03 max. 6 W.V.: 25Vmax. : 0.05 max. 6 R9 : 0.075max. 6 Q or 500Q •F(Whichever is smaller) 2 F(Whichever is smaller) 1 C or 500Q •F(Whichever is smaller) 2 F(Whichever is smaller) 1 Temp 1 R7/L8/R9: Within ±12.5% 1 R7/L8 W.V.: 35Vmin.: 0.035 max.* * GCM188L81H221 to 103 : 0.05 max. 1	Ap treation See ration 55 55 55 55 55 55 55 55 55 55 55 55 55	ply the 2 atment t for 24: ure	24-hour heat (shown below, ±2 hours at r Humidity 90-98% + Humidity 90 + Humidity 90 + Humidity 90% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity + Humidity 100% + Humidity + Humid	10 consecutive times com temperature, the 10 − 98% Humidity 80- 90 − 98% 40 10 − 10 − 10 10 − 10 1	h measure. idity 90~98% 90~98% 10 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1
5	Physical An Moisture Re	Appearance Capacitance Change Q/D.F. I.R. I.R.	The measured and observed chara specifications in the following table. No marking defects Within $\pm 3.0\%$ or ± 0.30 pF (Whichever is larger) 30 pFmin. : Q ≥ 350 10 pF and over, 30 pF and below: $Q \ge 275+5C/2$ 10 pFmax.: Q $\ge 200+10$ C C: Nominal Capacitance(pF) 5C/5G/R7/L8 : More than $10,000$ M2 R9 : More than 3000 MΩ or $150\Omega \cdot f$ Sector from the following table. No marking defects Within $\pm 3.0\%$ or ± 0.30 pF (Whichever is larger) 30 pF and over: Q ≥ 200 30 pF and below: Q $\ge 100+10C/3$ C: Nominal Capacitance(pF)	R7/L8/R9 : Within ±12.5% Temp (% R7/L8 : W.V.: 35Vmin.: 0.03 max. 6 W.V.: 25Vmax. : 0.05 max. 6 R9 : 0.075max. 6 Q or 500Q •F(Whichever is smaller) 2 F(Whichever is smaller) 1 C or 500Q •F(Whichever is smaller) 2 F(Whichever is smaller) 1 E(Whichever is smaller) 1 R7/L8/R9: Within ±12.5% 7 R7/L8 W.V.: 35Vmin.: 0.035 max.* * GCM188L81H221 to 103 : 0.05 max. W.V.: 25Vmax. : 0.05 max.	Ap treation See ration 55 55 55 55 55 55 55 55 55 55 55 55 55	ply the 2 atment t for 24: ure	24-hour heat (shown below, ±2 hours at r Humidity 90-98% + Humidity 90 + Humidity 90 + Humidity 90% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity + Humidity 100% + Humidity + Humid	10 consecutive times com temperature, the 10 − 98% Humidity 80- 90 − 98% 40 10 − 10 − 10 10 − 10 1	h measure. idity 90~98% 90~98% 10 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1
5	Physical An Moisture Re	Alysis Appearance Capacitance Change Q/D.F. I.R. I.R. Appearance Capacitance Change Q/D.F. Capacitance Change Q/D.F.	The measured and observed chara specifications in the following table. No marking defects Within $\pm 3.0\%$ or ± 0.30 pF (Whichever is larger) 30 pFmin. : Q ≥ 350 10 pF and over, 30 pF and below: $Q \ge 275+5C/2$ 10 pFmax.: Q $\ge 200+10C$ C: Nominal Capacitance(pF) 5C/5G/R7/L8 : More than $10,000$ M2 R9 : More than 3000 MΩ or 150Ω · f P = More than 3000 MΩ or 150Ω · f Whichever than 3000 MΩ or 150Ω · f Within $\pm 3.0\%$ or ± 0.30 pF (Whichever is larger) 30 pF and over: Q ≥ 200 30 pF and below: Q $\ge 100+10C/3$	R7/L8/R9 : Within ±12.5% Temp (% R7/L8 : W.V.: 35Vmin.: 0.03 max. 6 W.V.: 25Vmax. : 0.05 max. 6 R9 : 0.075max. 6 Q or 500Q •F(Whichever is smaller) 2 F(Whichever is smaller) 1 C or 500Q •F(Whichever is smaller) 2 F(Whichever is smaller) 1 E(Whichever is smaller) 1 R7/L8/R9: Within ±12.5% 7 R7/L8 W.V.: 35Vmin.: 0.035 max.* * GCM188L81H221 to 103 : 0.05 max. W.V.: 25Vmax. : 0.05 max.	Ap treating Seerating 55 55 55 55 55 55 55 55 55 55 55 55 55	ply the 2 atment t for 24: ure	24-hour heat (shown below, ±2 hours at r Humidity 90-98% + Humidity 90 + Humidity 90 + Humidity 90% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity 100% + Humidity + Humidity 100% + Humidity + Humid	10 consecutive times com temperature, the 10 − 98% Humidity 80- 90 − 98% 40 10 − 10 − 10 10 − 10 1	h measure. idity 90~98% 90~98% 10 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1

AEC-Q200 Murata Standard Specification and Test Methods

			Spo	ecification.	
No	AEC-Q20	0 Test Item	Temperature	High Dielectric Type	AEC-Q200 Test Method
7	Oneneticanel Li	4 -	Compensating Type The measured and observed chara	÷	
'	Operational Li	le	specifications in the following table	•	Apply 200% of the rated voltage for 1000 ± 12 hours at $125\pm3^{\circ}C$ (for $\Delta C/R7$), $150\pm3^{\circ}C$ (for $5G/L8/R9$).
		Appearance	No marking defects		Set for 24 ± 2 hours at room temperature, then measure.
		Capacitance	Within ±3.0% or ±0.30pF	R7/L8/R9: Within ±12.5%	The charge/discharge current is less than 50mA.
		Change	(Whichever is larger)		
		Q/D.F.	30pFmin. : Q≧350	R7/L8 : W.V.: 35Vmin.: 0.035 max.*	 Initial measurement for high dielectric constant type.
			10pF and over, 30pF and below:	* GCM155R71H 562 to 223: 0.05 max.	Apply 200% of the rated DC voltage for one hour at the maximum
			Q≧275+5C/2	GCM188L81H221 to 103 : 0.04 max.	operating temperature $\pm 3^{\circ}$ C. Remove and set for 24 ± 2 hours at
			10pFmax.: Q ≧200+10C	W.V.: 25Vmax. : 0.05 max.	room temperature. Perform initial measurement.
			C: Nominal Capacitance(pF)	R9 : 0.075max.	
		I.R.	More than 1,000MΩ or 50Ω · F		-
			(Whichever is smaller)		
8	External Visua	al	No defects or abnormalities		Visual inspection
9	Physical Dime	ension	Within the specified dimensions		Using calipers
10	Resistance to	Appearance	No marking defects		Per MIL-STD-202 Method 215
	Solvents	Capacitance	Within the specified tolerance		Solvent 1 : 1 part (by volume) of isopropyl alcohol
					3 parts (by volume) of mineral spirits
		Q/D.F.	30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.025 max.	Solvent 2 : Terpene defluxer
			30pFmax.: Q ≧400+20C	W.V.: 16V/10V : 0.035 max.	Solvent 3 : 42 parts (by volume) of water
			C: Nominal Capacitance(pF)	R9 : 0.05max.	1 part (by volume) of propylene glycol monomethyl ether 1 part (by volume) of monoethanolamine
		I.R.	More than 10,000MΩ or 500Ω · F		
			(Whichever is smaller)		
11	Mechanical	Appearance	No marking defects		Three shocks in each direction should be applied along 3 mutually
	Shock	Capacitance	Within the specified tolerance		perpendicular axes of the test specimen (18 shocks). The specified test pulse should be Half-sine and should have a
		Q/D.F.	30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.025 max.	duration :0.5ms, peak value:1500g and velocity change: 4.7m/s.
			30pFmax.: Q ≧400+20C	W.V.: 16V/10V : 0.035 max.	
			C: Nominal Capacitance(pF)	R9 : 0.05max.	
		I.R.	More than 10,000MΩ or 500Ω+F		-
			(Whichever is smaller)		
12	Vibration	Appearance	No defects or abnormalities		Solder the capacitor to the test jig (glass epoxy board) in the same
		Capacitance	Within the specified tolerance		manner and under the same conditions as (19). The capacitor should be subjected to a simple harmonic motion having a total
		Q/D.F.	30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.025 max.	amplitude of 1.5mm, the frequency being varied uniformly between
			30pFmax.: Q ≧400+20C	W.V.: 16V/10V : 0.035 max.	the approximate limits of 10 and 2000Hz. The frequency range, from
			C: Nominal Capacitance(pF)	R9 : 0.05max.	10 to 2000Hz and return to 10Hz, should be traversed in
		I.R.	More than 10,000MΩ or 500Ω · F	ļ	approximately 20 minutes. This motion should be applied for 12 items in each 3 mutually perpendicular directions (total of 36 times).
			(Whichever is smaller)		
13	Resistance to		The measured and observed chara	acteristics should satisfy the	Immerse the capacitor in a eutectic solder solution at 260±5°C for
	Soldering Hea	ıt	specifications in the following table		10±1 seconds. Set at room temperature for 24±2 hours, then
		Appearance	No marking defects		measure.
		Capacitance	Within the specified tolerance		Initial measurement for high dielectric constant type
		Q/D.F.	30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.025 max.	Perform a heat treatment at 150+0/-10 °C for one hour and then set
			30pFmax.: Q ≧400+20C	W.V.: 16V/10V : 0.035 max.	for 24 ± 2 hours at room temperature.
			C: Nominal Capacitance(pF)	R9 : 0.05max.	Perform the initial measurement.
		I.R.	More than 10,000MΩ or 500Ω · F		4
			(Whichever is smaller)		
			(**Tilonever is Stildlief)		

AEC-Q200 Murata Standard Specification and Test Methods

		Sp	ecification.			
lo AEC	C-Q200 Test Item	Temperature Compensating Type	High Dielectric Type		AEC-Q200	Test Method
4 Therma	al Shock	The measured and observed charac	cteristics should satisfy the	Fix the capacitor	to the supporting ji	g in the same manner and unde
		specifications in the following table.		the same conditio	ons as (19). Perforr	n the 300 cycles according to
	Appearance	No marking defects		the two heat treat	ments listed in the	following table(Maximum
	Capacitance	Within ±2.5% or ±0.25pF	R7/L8/R9: Within ±10.0%	transfer time is 20) seconds). Set fo	r 24±2 hours at room
	Change	(Whichever is larger)		temperature, then	measure	
	Q/D.F.	30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.03 max.*	Oten	4	2
		30pFmax.: Q ≧400+20C	* GCM188R7 1E/1H 563 to 104:0.05 max.	Step	1	
		C: Nominal Capacitance(pF)	W.V.: 16V/10V : 0.05 max.	Temp. (°C)	-55+0/-3	125+3/-0 (for∆C/R7) 150+3/-0 (for 5G/L8/R9)
			R9 : 0.075max	Time	15±3	15±3
	I.R.	More than $10,000M\Omega$ or $500\Omega \cdot F$	•	(min.)	13±3	15±5
		(Whichever is smaller)				
				Initial measurem	ent for high dielect	ric constant type
					-	10 °C for one hour and then se
					room temperature	
				Perform the initial		•
5 ESD	Appearance	No marking defects		Per AEC-Q200-00		
5 200	Capacitance	Within the specified tolerance		1 61 ALC-Q200-00	02	
	Capacitanee	Within the specified tolerance				
	Q/D.F.	30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.025 max.	1		
	G/D.I.	30pFmax.: Q ≧400+20C	W.V.: 16V/10V :0.035 max.	1		
		C: Nominal Capacitance(pF)	R9 : 0.05max.	1		
		ο. ποιτιπαι σαμασιταποε(μη)	1.0 . 0.00max.			
	I.R.	More than 10,000MΩ or 500Ω · F	1	-		
		(Whichever is smaller)		1		
16 Soldera	ability	95% of the terminations is to be solo	dered evenly and continuously.	(a) Preheat at 155	5°C for 4 hours. Aft	er preheating, immerse the
-				. ,		JIS-K-8101) and rosin (JIS-K-
				-	sin in weight propo	
						0.5 seconds at 235±5°C.
				outoono ooluoi		
				(b) should be place	ed into steam agir	ng for 8 hours±15 minutes.
					-	pacitor in a solution of
					-	
1						IS-K-5902) (25% rosin in weight
				proportion). Im	merse in eutectic	solder solution for 5+0/-0.5
					merse in eutectic	
				proportion). Im seconds at 23	imerse in eutectic s 5±5°C.	solder solution for 5+0/-0.5
				proportion). Im seconds at 23 (c) should be plac	merse in eutectic s $5\pm5^{\circ}$ C.	solder solution for 5+0/-0.5
				proportion). Im seconds at 23 (c) should be plac After preheatin	merse in eutectic s 5±5°C. Red into steam agin ng, immerse the ca	solder solution for 5+0/-0.5 ng for 8 hours±15 minutes. pacitor in a solution of
				proportion). Im seconds at 23 (c) should be plac After preheatin ethanol(JIS-K-	merse in eutectic s 5±5°C. ed into steam agir ig, immerse the ca 8101) and rosin (JI	solder solution for 5+0/-0.5 ng for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight
				c) should be plac After preheatin ethanol(JIS-K- proportion). Im	merse in eutectic s 5±5°C. eed into steam agir ig, immerse the ca 8101) and rosin (JI merse in eutectic s	solder solution for 5+0/-0.5 ng for 8 hours±15 minutes. pacitor in a solution of
				proportion). Im seconds at 23 (c) should be plac After preheatin ethanol(JIS-K-	merse in eutectic s 5±5°C. eed into steam agir ig, immerse the ca 8101) and rosin (JI merse in eutectic s	solder solution for 5+0/-0.5 ng for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight
17 Electric	cal Appearance	No defects or abnormalities		c) should be plac After preheatin ethanol(JIS-K- proportion). Im	merse in eutectic s 5±5°C. ed into steam agir ig, immerse the ca 8101) and rosin (JI imerse in eutectic s)±5°C.	solder solution for 5+0/-0.5 ng for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight
17 Electric Chatac		No defects or abnormalities Within the specified tolerance		 proportion). Im seconds at 234 (c) should be place After preheatine thanol(JIS-K-proportion). Im seconds at 260 Visual inspection. 	merse in eutectic s 5±5°C. eved into steam agir ig, immerse the ca 8101) and rosin (JI imerse in eutectic s)±5°C.	solder solution for 5+0/-0.5 ng for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight
				c) should be place After preheatin ethanol(JIS-K- proportion). Im seconds at 260 Visual inspection. The capacitance/	merse in eutectic s 5±5°C. eved into steam agir ig, immerse the ca 8101) and rosin (JI imerse in eutectic s)±5°C.	solder solution for 5+0/-0.5 ng for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 neasured at 25°C at the
Chatac		Within the specified tolerance	R7/L8 : W.V.: 25Vmin.: 0.025 max.	 proportion). Im seconds at 234 (c) should be place After preheatine thanol(JIS-K-proportion). Im seconds at 260 Visual inspection. The capacitance/(frequency and volume) 	merse in eutectic s 5±5°C. eed into steam agin g, immerse the ca 8101) and rosin (JI imerse in eutectic s 0)±5°C. Q/D.F. should be n	solder solution for 5+0/-0.5 ng for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 neasured at 25°C at the table.
Chatac	teri- Capacitance	Within the specified tolerance 30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.025 max. W.V.: 16V/10V : 0.035 max.	c) should be place After preheatin ethanol(JIS-K- proportion). Im seconds at 260 Visual inspection. The capacitance/	merse in eutectic s $5\pm5^{\circ}C$. eved into steam agir ig, immerse the ca 8101) and rosin (JI immerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be in Itage shown in the $\Delta C.5G$	solder solution for 5+0/-0.5 ng for 8 hours \pm 15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120 \pm 5 neasured at 25°C at the table. $\Delta C,5G$ (more than 1000pF)
Chatac	teri- Capacitance	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C	W.V.: 16V/10V : 0.035 max.	c) should be place After preheatin ethanol(JIS-K- proportion). Im seconds at 260 Visual inspection. The capacitance/u frequency and vol	merse in eutectic s 5±5°C. eed into steam agin g, immerse the ca 8101) and rosin (JI imerse in eutectic s 0±5°C. Q/D.F. should be n Itage shown in the	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 neasured at 25°C at the table. $\Delta C,5G$ (more than 1000pF) R7,R9,L8
Chatac	teri- Capacitance	Within the specified tolerance 30pFmin. : Q≧1000		 proportion). Im seconds at 234 (c) should be place After preheatine thanol(JIS-K-proportion). Im seconds at 260 Visual inspection. The capacitance/(frequency and volume) 	merse in eutectic s $5\pm5^{\circ}C$. eved into steam agir ig, immerse the ca 8101) and rosin (JI immerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be in Itage shown in the $\Delta C.5G$	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 neasured at 25°C at the table. $\frac{\Delta C,5G}{(more than 1000pF)} R7,R9,L8 (C \leq 10 \mu F)$
Chatac	teri- Capacitance	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C	W.V.: 16V/10V : 0.035 max.	c) should be place After preheatin ethanol(JIS-K- proportion). Im seconds at 260 Visual inspection. The capacitance/ frequency and vol	merse in eutectic s $5\pm5^{\circ}C$. red into steam agin ig, immerse the ca 8101) and rosin (JI imerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be n itage shown in the $\Delta C,5G$ (1000 pF and b	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 neasured at 25°C at the table. $\frac{\Delta C,5G}{(more than 1000pF)} R7,R9,L8 (C \leq 10 \mu F)$ 1±0.1kHz
Chatac	teri- Capacitance	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C	W.V.: 16V/10V : 0.035 max.	c) should be place After preheatin ethanol(JIS-K- proportion). Im seconds at 260 Visual inspection. The capacitance/ frequency and vol Char. Item Frequency	merse in eutectic s $5\pm5^{\circ}C$. red into steam agin ig, immerse the ca 8101) and rosin (JI imerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be n itage shown in the $\Delta C,5G$ (1000 pF and b $1\pm0.1MHz$	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 neasured at 25°C at the table. $\frac{\Delta C,5G}{(more than 1000pF)} R7,R9,L8 (C \leq 10 \mu F)$ 1±0.1kHz
Chatac	teri- Capacitance Q/D.F.	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C C: Nominal Capacitance(pF)	W.V.: 16V/10V : 0.035 max. R9 : 0.05max.	c) should be place After preheatin ethanol(JIS-K- proportion). Im seconds at 260 Visual inspection. The capacitance// frequency and vol Char. Item Frequency Voltage	merse in eutectic s $5\pm5^{\circ}C$. red into steam agin ig, immerse the ca 8101) and rosin (JI immerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be in itage shown in the $\Delta C,5G$ (1000 pF and b $1\pm0.1MHz$ 0.5 to 5Vrm	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 neasured at 25°C at the table. $\frac{\Delta C,5G}{(more than 1000pF)}$ R7,R9,L8 (C≤10 μ F) 1±0.1kHz is 1±0.2Vrms
Chatac	teri- Capacitance	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C C: Nominal Capacitance(pF) More than 100,000MΩ or 1000Ω⋅F	W.V.: 16V/10V : 0.035 max. R9 : 0.05max. More than 10,000MΩ or 500Ω+F	proportion). Im seconds at 234 (c) should be place After preheatin ethanol(JIS-K- proportion). Im seconds at 260 Visual inspection. The capacitance/u frequency and vol Char. Item Frequency Voltage	merse in eutectic s $5\pm5^{\circ}C$. red into steam agin ig, immerse the ca 8101) and rosin (JI immerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be in itage shown in the $\Delta C,5G$ (1000 pF and b $1\pm0.1MHz$ 0.5 to 5Vrm istance should be	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 neasured at 25°C at the table. $\frac{\Delta C,5G}{(more than 1000pF)}$ R7,R9,L8 (C≦10 μ F) 1±0.1kHz is 1±0.2Vrms measured with a DC voltage no
Chatac	teri- Capacitance Q/D.F.	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C C: Nominal Capacitance(pF)	W.V.: 16V/10V : 0.035 max. R9 : 0.05max.	proportion). Im seconds at 234 (c) should be place After preheating ethanol(JIS-K-proportion). Im seconds at 260 Visual inspection. The capacitance/4 frequency and vol Char. Item Frequency Voltage	merse in eutectic s $5\pm5^{\circ}C$. red into steam agin ig, immerse the ca 8101) and rosin (JI immerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be in itage shown in the $\Delta C,5G$ (1000 pF and b $1\pm0.1MHz$ 0.5 to 5Vrm istance should be	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 measured at 25°C at the table. $\Delta C,5G$ (more than 1000pF) R7,R9,L8 (C≤10 μ F) 1±0.1kHz Is 1±0.2Vms measured with a DC voltage no and 125°C(for $\Delta C/R7$)/
Chatac	I.R. 25°C	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C C: Nominal Capacitance(pF) More than 100,000MΩ or 1000Ω • F (Whichever is smaller)	W.V.: 16V/10V : 0.035 max. R9 : 0.05max. More than 10,000MΩ or 500Ω+F (Whichever is smaller)	proportion). Im seconds at 234 (c) should be place After preheating ethanol(JIS-K-proportion). Im seconds at 260 Visual inspection. The capacitance/4 frequency and vol Char. Item Frequency Voltage	merse in eutectic s $5\pm5^{\circ}C$. red into steam agin ig, immerse the ca 8101) and rosin (JI imerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be in tage shown in the 1\pm0.1MHz 0.5 to 5Vrm istance should be ed voltage at $25^{\circ}C$	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 measured at 25°C at the table. $\Delta C,5G$ (more than 1000pF) R7,R9,L8 (C≤10 μ F) 1±0.1kHz Is 1±0.2Vms measured with a DC voltage no and 125°C(for $\Delta C/R7$)/
Chatac	teri- Capacitance Q/D.F.	 Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C C: Nominal Capacitance(pF) More than 100,000MΩ or 1000Ω · F (Whichever is smaller) More than 10,000MΩ or 100Ω · F 	W.V.: 16V/10V : 0.035 max. R9 : 0.05max. More than 10,000MΩ or 500Ω • F (Whichever is smaller) More than 1,000MΩ or 10Ω • F	proportion). Im seconds at 234 (c) should be place After preheating ethanol(JIS-K-proportion). Im seconds at 260 Visual inspection. The capacitance/4 frequency and vol Char. Item Frequency Voltage	merse in eutectic s $5\pm5^{\circ}C$. red into steam agin ig, immerse the ca 8101) and rosin (JI imerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be in tage shown in the 1\pm0.1MHz 0.5 to 5Vrm istance should be ed voltage at $25^{\circ}C$	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 measured at 25°C at the table. $\Delta C,5G$ (more than 1000pF) R7,R9,L8 (C≤10 μ F) 1±0.1kHz Is 1±0.2Vms measured with a DC voltage no and 125°C(for $\Delta C/R7$)/
Chatac	I.R. 25°C	Within the specified tolerance 30pFmin. : Q≧1000 30pFmax.: Q≧400+20C C: Nominal Capacitance(pF) More than 100,000MΩ or 1000Ω • F (Whichever is smaller)	W.V.: 16V/10V : 0.035 max. R9 : 0.05max. More than 10,000MΩ or 500Ω+F (Whichever is smaller)	proportion). Im seconds at 234 (c) should be place After preheating ethanol(JIS-K-proportion). Im seconds at 260 Visual inspection. The capacitance/4 frequency and vol Char. Item Frequency Voltage	merse in eutectic s $5\pm5^{\circ}C$. red into steam agin ig, immerse the ca 8101) and rosin (JI imerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be in tage shown in the 1\pm0.1MHz 0.5 to 5Vrm istance should be ed voltage at $25^{\circ}C$	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 measured at 25°C at the table. $\Delta C,5G$ (more than 1000pF) R7,R9,L8 (C≤10 μ F) 1±0.1kHz Is 1±0.2Vms measured with a DC voltage no and 125°C(for $\Delta C/R7$)/
Chatac	I.R. 25°C	Within the specified tolerance $30pFmin. : Q \ge 1000$ $30pFmax.: Q \ge 400+20C$ C: Nominal Capacitance(pF) More than 100,000M Ω or 1000 Ω ·F (Whichever is smaller) More than 10,000M Ω or 100 Ω ·F (Whichever is smaller)	W.V.: 16V/10V : 0.035 max. R9 : 0.05max. More than 10,000MΩ or 500Ω • F (Whichever is smaller) More than 1,000MΩ or 10Ω • F	proportion). Im seconds at 234 (c) should be place After preheating ethanol(JIS-K-proportion). Im seconds at 260 Visual inspection. The capacitance/4 frequency and vol Char. Item Frequency Voltage	merse in eutectic s $5\pm5^{\circ}C$. red into steam agin ig, immerse the ca 8101) and rosin (JI imerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be in tage shown in the 1\pm0.1MHz 0.5 to 5Vrm istance should be ed voltage at $25^{\circ}C$	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 measured at 25°C at the table. $\Delta C,5G$ (more than 1000pF) R7,R9,L8 (C≤10 μ F) 1±0.1kHz Is 1±0.2Vms measured with a DC voltage no and 125°C(for $\Delta C/R7$)/
Chatac	I.R. 25°C	Within the specified tolerance $30pFmin. : Q \ge 1000$ $30pFmax.: Q \ge 400+20C$ C: Nominal Capacitance(pF) More than 100,000M Ω or 1000 Ω ·F (Whichever is smaller) More than 10,000M Ω or 100 Ω ·F (Whichever is smaller) More than 10,000M Ω or 100 Ω ·F	W.V.: 16V/10V : 0.035 max. R9 : 0.05max. More than 10,000MΩ or 500Ω • F (Whichever is smaller) More than 1,000MΩ or 10Ω • F (Whichever is smaller) More than 1,000MΩ or 10Ω • F (Whichever is smaller)	proportion). Im seconds at 234 (c) should be place After preheating ethanol(JIS-K-proportion). Im seconds at 260 Visual inspection. The capacitance/4 frequency and vol Char. Item Frequency Voltage	merse in eutectic s $5\pm5^{\circ}C$. red into steam agin ig, immerse the ca 8101) and rosin (JI imerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be in tage shown in the 1\pm0.1MHz 0.5 to 5Vrm istance should be ed voltage at $25^{\circ}C$	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 measured at 25°C at the table. $\Delta C,5G$ (more than 1000pF) R7,R9,L8 (C≤10 μ F) 1±0.1kHz Is 1±0.2Vms measured with a DC voltage no and 125°C(for $\Delta C/R7$)/
Chatac	I.R. 25°C	Within the specified tolerance $30pFmin. : Q \ge 1000$ $30pFmax.: Q \ge 400+20C$ C: Nominal Capacitance(pF) More than 100,000M Ω or 1000 Ω ·F (Whichever is smaller) More than 10,000M Ω or 100 Ω ·F (Whichever is smaller)	W.V.: 16V/10V : 0.035 max. R9 : 0.05max. More than 10,000MΩ or 500Ω • F (Whichever is smaller) More than 1,000MΩ or 10Ω • F (Whichever is smaller)	proportion). Im seconds at 234 (c) should be place After preheating ethanol(JIS-K-proportion). Im seconds at 260 Visual inspection. The capacitance/4 frequency and vol Char. Item Frequency Voltage	merse in eutectic s $5\pm5^{\circ}C$. red into steam agin ig, immerse the ca 8101) and rosin (JI imerse in eutectic s $0\pm5^{\circ}C$. Q/D.F. should be in tage shown in the 1\pm0.1MHz 0.5 to 5Vrm istance should be ed voltage at $25^{\circ}C$	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 measured at 25°C at the table. $\Delta C,5G$ (more than 1000pF) R7,R9,L8 (C≤10 μ F) 1±0.1kHz Is 1±0.2Vms measured with a DC voltage no and 125°C(for $\Delta C/R7$)/
Chatac	I.R. 25°C	Within the specified tolerance $30pFmin. : Q \ge 1000$ $30pFmax.: Q \ge 400+20C$ C: Nominal Capacitance(pF) More than 100,000M Ω or 1000 Ω ·F (Whichever is smaller) More than 10,000M Ω or 100 Ω ·F (Whichever is smaller) More than 10,000M Ω or 100 Ω ·F (Whichever is smaller)	W.V.: 16V/10V : 0.035 max. R9 : 0.05max. More than 10,000MΩ or 500Ω • F (Whichever is smaller) More than 1,000MΩ or 10Ω • F (Whichever is smaller) More than 1,000MΩ or 10Ω • F (Whichever is smaller)	c) should be place After preheatin ethanol(JIS-K- proportion). Im seconds at 260 Visual inspection. The capacitance// frequency and vol Char. Item Frequency Voltage	merse in eutectic s $5\pm5^{\circ}$ C. red into steam agir ag, immerse the ca 8101) and rosin (JI imerse in eutectic s 0) $\pm5^{\circ}$ C. Q/D.F. should be n itage shown in the Δ C,5G (1000 pF and b 1 \pm 0.1MHz 0.5 to 5Vrm istance should be ed voltage at 25°C R9) within 2 minute	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 measured at 25°C at the table. $\Delta C,5G$ (more than 1000pF) R7,R9,L8 (C≤10 μ F) 1±0.1kHz Is 1±0.2Vms measured with a DC voltage no and 125°C(for $\Delta C/R7$)/
Chatac	I.R. 25°C	Within the specified tolerance $30pFmin. : Q \ge 1000$ $30pFmax.: Q \ge 400+20C$ C: Nominal Capacitance(pF) More than 100,000M Ω or 1000 Ω ·F (Whichever is smaller) More than 10,000M Ω or 100 Ω ·F (Whichever is smaller) More than 10,000M Ω or 100 Ω ·F	W.V.: 16V/10V : 0.035 max. R9 : 0.05max. More than 10,000MΩ or 500Ω • F (Whichever is smaller) More than 1,000MΩ or 10Ω • F (Whichever is smaller) More than 1,000MΩ or 10Ω • F (Whichever is smaller)	proportion). Im seconds at 234 (c) should be place After preheatin ethanol(JIS-K-proportion). Im seconds at 260 Visual inspection. The capacitance/t frequency and vol Char. Item Frequency Voltage The insulation resexceeding the rate 150°C (for 5G/L8/f No failure should	merse in eutectic s $5\pm5^{\circ}$ C. red into steam agir rg, immerse the ca 8101) and rosin (JI imerse in eutectic s 0) $\pm5^{\circ}$ C. Q/D.F. should be n Itage shown in the Δ C,5G (1000 pF and b 1 \pm 0.1MHz 0.5 to 5Vrm istance should be ed voltage at 25°C R9) within 2 minute be observed when	solder solution for 5+0/-0.5 Ing for 8 hours±15 minutes. pacitor in a solution of IS-K-5902) (25% rosin in weight solder solution for 120±5 measured at 25°C at the table. $\frac{\Delta C,5G}{(more than 1000pF)}$ R7,R9,L8 (C ≤ 10 µ F) 1±0.1kHz Is 1±0.2Vrms measured with a DC voltage nor and 125°C(for $\Delta C/R7$)/ is of charging.

AEC-Q200 Murata Standard Specification and Test Methods

No	AEC-Q200	Test Item	Sp Temperature	ecification.	AEC-Q200 Test Method
110	ALO Q200	103t ftom	Compensating Type	High Dielectric Type	
18	Board Flex	Appearance	No marking defects		Solder the capacitor on the test jig (glass epoxy board) shown in Fig1 using a eutectic solder. Then apply a force in the direction
		Capacitance	Within ±5.0% or ±0.5pF	R7/L8/R9: Within ±10.0%	shown in Fig 2 for 5±1sec. The soldering should be done by the
		Change Q/D.F.	(Whichever is larger)	R7/L8 : W.V.: 25Vmin.: 0.025 max.	reflow method and should be conducted with care so that the
		Q/D.F.	30pFmin. : Q≧1000	W.V.: 16V/10V : 0.035max.	soldering is uniform and free of defects such as heat shock.
			30pFmax.: Q ≧400+20C C: Nominal Capacitance(pF)		Type a b c GCM03 0.3 0.9 0.3
			C: Nominal Capacitance(pF)	R9 : 0.05max.	GCM03 0.3 0.9 0.3 GCM15 0.5 1.5 0.6
		I.R.	No		GCM18 0.6 2.2 0.9
			More than 10,000MΩ or 500Ω	2•F	GCM21 0.8 3.0 1.3 GCM31 2.0 4.4 1.7
			(Whichever is smaller)		GCM32 2.0 4.4 2.6
				, b ,	(in mm)
					Pressurizing speed:1.0mm/s Pressurize Flexure : ≦2 (High Dielectric Type)
			F	ig. 1 t : 1.6mm	45 45 Flexure : ≦3
					(Temperature
					Fig. 2
19	Terminal	Appearance	No marking defects		Solder the capacitor to the test jig (glass epoxy board) shown in
	Strength	Capacitance	Within specified tolerance		Fig.3 using a eutectic solder. Then apply *18N force in parallel with the test jig for 60sec.
		Capacitance	within specified tolerance		The soldering should be done either with an iron or using the reflow
		Q/D.F.	30pFmin. : Q≧1000	R7/L8 : W.V.: 25Vmin.: 0.025 max.	method and should be conducted with care so that the soldering is
		G/D.I .	30pFmax.: Q ≧400+20C	W.V.: 16V/10V : 0.035max.	uniform and free of defects such as heat shock
			C: Nominal Capacitance(pF)		*2N(GCM03/15)
			,		Type a b c
		I.R.	More than 10,000MΩ or 500Ω (Whichever is smaller)	2·F	GM03 0.3 0.9 0.3 GCM15 0.4 1.5 0.5 GCM18 1.0 3.0 1.2 GCM21 1.2 4.0 1.65 GCM31 2.2 5.0 2.0 GCM32 2.2 5.0 2.9
					Solder resist
					Baked electrode or Copper foil
20	Beam Load Test	1	Destruction value should be e		Fig.3 Place the capacitor in the beam load fixture as Fig 4.
20	Lean Luad 16St		< Chip L dimension : 2.5mm Chip thicknes Chip thicknes Chip thicknes Chip thicknes	max. > ss > 0.5mm rank : 20N ss = 0.5mm rank : 8N ss = 0.3mm rank : 5N s < 0.3mm rank : 2.5N	Apply a force. < Chip Length : 2.5mm max. >
				min. > s < 1.25mm rank : 15N is ≧ 1.25mm rank : 54.5N	< Chip Length : 3.2mm min. >
					Speed supplied the Stress Load : *0.5mm/s *GCM03: 0.1mm/s

■AEC-Q200 Murata Standard Specification and Test Methods

			Speci	fication.	
No	AEC-Q2	200 Test Item	Temperature Compensating Type	High Dielectric Type	AEC-Q200 Test Method
21	Capacitance	Capacitance	Within the specified tolerance.	R7 : Within ±15%	The capacitance change should be measured after 5 min. at
	Temperature	Change	(Table A)	(-55°C to +125°C)	each specified temperature stage.
	Characteristics			L8 : Within ±15%	(1)Temperature Compensating Type
				(-55°C to +125°C)	The temperature coefficient is determined using the capacitance
				Within +15/-40%	measured in step 3 as a reference. When cycling the temperature
				(+125°C to +150°C)	sequentially from step1 through 5 (Δ C: +25°C to +125°C,
				R9 : Within ±15%	5G:+25°C to +150°C other temp. coeffcient.:+25°C to +85°C) the
				(-55°C to +150°C)	capacitance should be within the specified tolerance for the
					temperature coefficient and capacitance change as Table A-1. The
					capacitance drift is calculated by dividing the differences
					between the maximum and minimum measured values in the step
		Temperature	Within the specified tolerance.		1,3 and 5 by the cap value in step 3.
		Coefficient	(Table A)		Step Temperature.(°C)
					1 25±2
					2 -55±3
					3 25±2
					4 125±3(for ΔC/R7), 150±3(for 5G/R9/L8),85±3(for other TC)
		Capacitance	Within ±0.2% or ±0.05 pF	7 /	5 25±2
		Drift	(Whichever is larger.)		
					(2) High Dielectric Constant Type
					The ranges of capacitance change compared with the above $25^{\circ}C$
					value over the temperature ranges shown in the table should be
					within the specified ranges.
					·Initial measurement for high dielectric constant type.
					Perform a heat treatment at 150+0/-10°C for one hour
				/	and then set for 24±2 hours at room temperature.
				\mathbf{V}	Perform the initial measurement.

Table A

	Naminal Values		Capa	citance Char	nge from 25°	C (%)	
Char.	Nominal Values (ppm/°C)	-5	55	-3	30	-1	0
		Max.	Min.	Max.	Min.	Max.	Min.
5C/5G	0± 30	0.58	-0.24	0.40	-0.17	0.25	-0.11

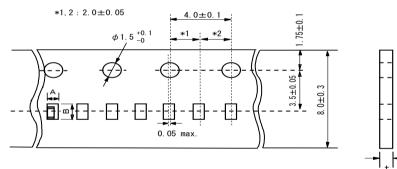
Note 1: Nominal values denote the temperature coefficient within a range of 25°C to 125°C(for Δ C)/ 150°C(for 5G).

1.Tape Carrier Packaging(Packaging Code:D/E/W/F/L/J/K)

			φ180mm reel		φ330m	m reel
	Туре	Paper	[.] Tape	Plastic Tape	Paper Tape	Plastic Tape
		Code:D/E	Code:W	Code:L	Code:J/ F	Code:K
GCM03		15000(W8P2)	30000(W8P1)		50000(W8P2)	
GCM15	5 (Dimensions Tolerance:±0.05)	10000(W8P2)	20000(W8P1)		50000(W8P2)	
GCIVITS	5 (Dimensions Tolerance:±0.1min.)	10000(W8P2)			40000(W8P2)	
GCM18		4000			10000	
	6	4000			10000	
GCM21	9	4000			10000	
	В			3000		10000
	6	4000			10000	
GCM31	9	4000			10000	
GCIVIST	M			3000		10000
	С			2000		6000
	9	4000			10000	
GCM32	Μ			3000		10000
3010132	Ν			2000		8000
	R/D/E			1000		4000
	Μ			1000		5000
GCM43	N/R			1000		4000
	E			500		2000
GCM55	Μ			1000		5000
0010100	N/R			1000		4000

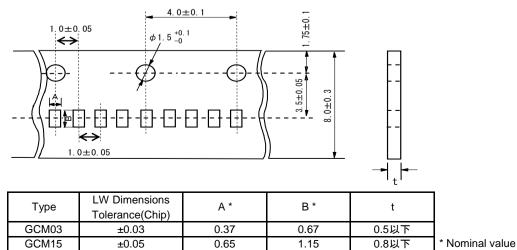
1.2 Dimensions of Tape

(1)GCM03/15 <Paper Tape W8P2 CODE:D/E/J/F>



				L	_
Ture e	LW Dimensions	A *O	D *0		
Туре	Tolerance(Chip)	A *3	B *3	t	
GCM03	±0.03	0.37	0.67	0.5 max.	
	±0.05	0.65	1.15		
GCM15	±0.1	0.70	1.20	0.8 max.	
	±0.2	0.75	1.35		*3 Nominal value

(2)GCM03/15 <Paper Tape W8P1 CODE:W>



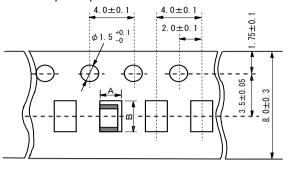
(in mm)

(in mm)

JEMCGP-01894F

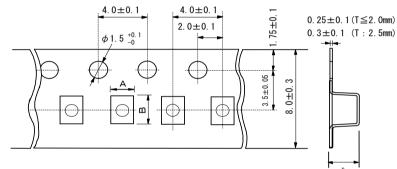
Package GCM Type

(3)GCM18/21/31/32 <Paper Tape>



Туре		LW Dimensions Tolerance(Chip)	T Dimensions (Chip)	А	В	t
GCM18	8	±0.1	0.8±0.1	1.05±0.10	1.85±0.10	
GCM21	6	±0.15	0.6±0.1	1.55±0.15	2.30±0.15	
GCIVIZI	9	±0.15	0.85±0.1	1.55±0.15	2.30±0.13	1.1 max.
GCM31	9	±0.15	0.85±0.1	2.00±0.20	3.60±0.20	
GCM32	9	L:±0.3/W:±0.2	0.85+0.15/-0.05	2.80±0.20	3.60±0.20	

(4)GCM21/31/32 <Plastic Tape>

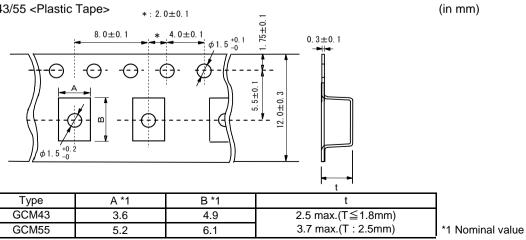


(in mm)

(in mm)

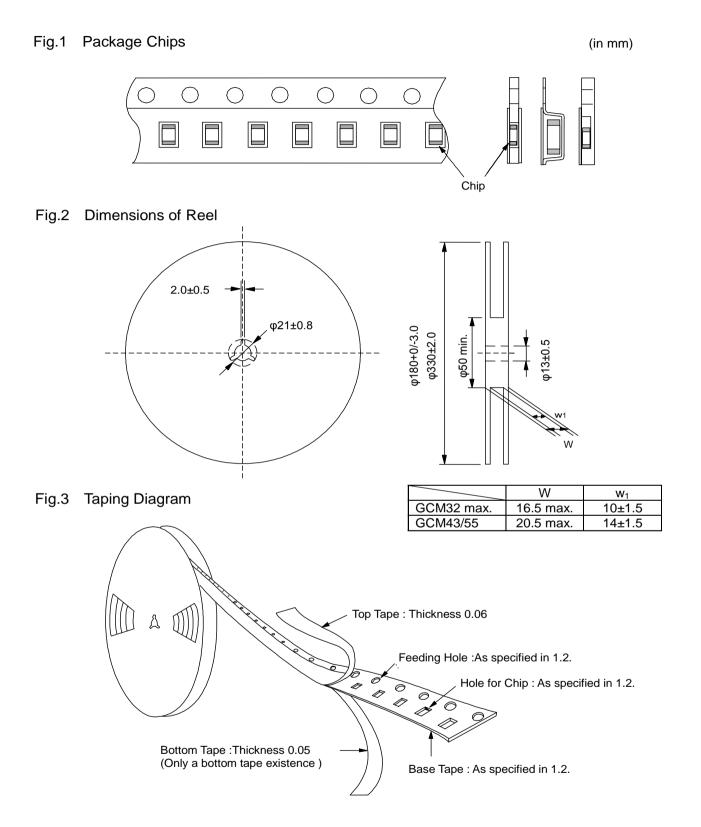
	t t					
Туре		LW Dimensions	T Dimensions	А	В	+
тур	C	Tolerance(Chip)	(Chip)	~	Б	L
GCM21	В	±0.15	1.25±0.15	1.45±0.20	2.25±0.20	2.0 max.
GCIVIZI	Б	±0.2	1.25±0.2	1.50±0.20	2.30±0.20	2.0 max.
	M C	±0.15	1.15±0.1	1.90±0.20	3.50±0.20	1.7 max.
GCM31		±0.2	1.15±0.15			
000001		±0.2	1.6±0.2			2.5 max.
		±0.3	1.6±0.3	2.10±0.20	3.60±0.20	2.5 max.
	М		1.15±0.1			1.7 max.
	Ν	L:±0.3	1.35±0.15			2.5 max.
GCM32	R	L.±0.3 W:±0.2	1.8±0.2	2.80±0.20	3.50±0.20	3.0 max.
	D	VV.±0.2 2.0±0.2	2.0±0.2			S.0 max.
	E		2.5±0.2			3.7 max.

(5)GCM43/55 <Plastic Tape>



JEMCGP-01894F

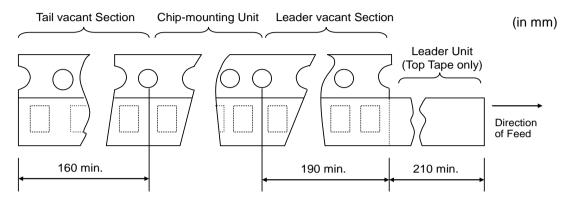
Package GCM Type



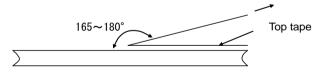
1.3 Tapes for capacitors are wound clockwise shown in Fig.3.

(The sprocket holes are to the right as the tape is pulled toward the user.)

1.4 Part of the leader and part of the vacant section are attached as follows.



- 1.5 Accumulate pitch : 10 of sprocket holes pitch = 40 ± 0.3 mm
- 1.6 Chip in the tape is enclosed by top tape and bottom tape as shown in Fig.1.
- 1.7 The top tape and base tape are not attached at the end of the tape for a minimum of 5 pitches.
- 1.8 There are no jointing for top tape and bottom tape.
- 1.9 There are no fuzz in the cavity.
- 1.10 Break down force of top tape : 5N min. Break down force of bottom tape : 5N min. (Only a bottom tape existence)
- 1.11 Reel is made by resin and appearance and dimension is shown in Fig 2. There are possibly to change the material and dimension due to some impairment.
- 1.12 Peeling off force : 0.1N to $0.6N^{*}$ in the direction as shown below. * GCM03:0.05N to 0.5N



1.13 Label that show the customer parts number, our parts number, our company name, inspection number and quantity, will be put in outside of reel.

Limitation of Applications

Please contact us before using our products for the applications listed below which require especially high reliability for the prevention of defects which might directly cause damage to the third party's life, body or property.

①Aircraft equipment
 ②Aerospace equipment
 ③Undersea equipment
 ④Power plant control equipment
 ⑤Medical equipment
 ⑥Transportation equipment(vehicles,trains,ships,etc.)
 ⑦Traffic signal equipment
 ⑧Data-processing equipment
 ⑩Application of similar complexity and/or reliability requirements to the applications listed in the above.

■ Storage and Operation condition

1. The performance of chip monolithic ceramic capacitors may be affected by the storage conditions.

- 1-1. Store the capacitors in the following conditions: Room Temperature of +5°C to +40°C and a Relative Humidity of 20% to 70%.
 - Sunlight, dust, rapid temperature changes, corrosive gas atmosphere or high temperature and humidity conditions during storage may affect solderability and packaging performance. Therefore, please maintain the storage temperature and humidity. Use the product within six months, as prolonged storage may cause oxidation of the electrodes.
 - (2) Please confirm solderability before using after six months.
 Store the capacitors without opening the original bag.
 Even if the storage period is short, do not exceed the specified atmospheric conditions.
- 1-2. Corrosive gas can react with the termination (external) electrodes or lead wires of capacitors, and result in poor solderability. Do not store the capacitors in an atmosphere consisting of corrosive gas (e.g.,hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.).
- 1-3. Due to moisture condensation caused by rapid humidity changes, or the photochemical change caused by direct sunlight on the terminal electrodes and/or the resin/epoxy coatings, the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or in high huimidity conditions

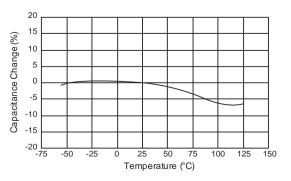
Rating

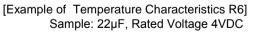
1.Temperature Dependent Characteristics

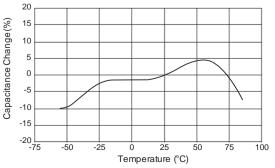
1. The electrical characteristics of the capacitor can change with temperature.

- 1-1. For capacitors having larger temperature dependency, the capacitance may change with temperature changes. The following actions are recommended in order to ensure suitable capacitance values.
 - (1) Select a suitable capacitance for the operating temperature range.
 - (2) The capacitance may change within the rated temperature. When you use a high dielectric constant type capacitors in a circuit that needs a tight (narrow) capacitance tolerance (e.g., a time-constant circuit), please carefully consider the temperature characteristics, and carefully confirm the various characteristics in actual use conditions and the actual system.

[Example of Temperature Characteristics R7] Sample: 0.1µF, Rated Voltage 50VDC







2.Measurement of Capacitance

- 1. Measure capacitance with the voltage and frequency specified in the product specifications.
- 1-1. The output voltage of the measuring equipment may decrease occasionally when capacitance is high. Please confirm whether a prescribed measured voltage is impressed to the capacitor.
- 1-2. The capacitance values of high dielectric constant type capacitors change depending on the AC voltage applied. Please consider the AC voltage characteristics when selecting a capacitor to be used in a AC circuit.

3.Applied Voltage

- 1. Do not apply a voltage to the capacitor that exceeds the rated voltage as called out in the specifications.
- 1-1. Applied voltage between the terminals of a capacitor shall be less than or equal to the rated voltage.
- (1) When AC voltage is superimposed on DC voltage, the zero-to-peak voltage shall not exceed the rated DC voltage. When AC voltage or pulse voltage is applied, the peak-to-peak voltage shall not exceed the rated DC voltage.
- (2) Abnormal voltages (surge voltage, static electricity, pulse voltage, etc.) shall not exceed the rated DC voltage.



(E : Maximum possible applied voltage.)

1-2. Influence of over voltage

Over voltage that is applied to the capacitor may result in an electrical short circuit caused by the breakdown of the internal dielectric layers .

The time duration until breakdown depends on the applied voltage and the ambient temperature.

4.Type of Applied Voltage and Self-heating Temperature

1.Confirm the operating conditions to make sure that nolarge current is flowing into the capacitor due to the continuous application of an AC voltage or pulse voltage.

When a DC rated voltage product is used in an AC voltage circuit or a pulse voltage circuit, the AC current or pulse current will flow into the capacitor; therefore check the self-heating condition.

Please confirm the surface temperature of the capacitor so that the temperature remains within the upper limits of the operating temperature, including the rise in temperature due to self-heating. When the capacitor is used with a high-frequency voltage or pulse voltage, heat may be generated by dielectric loss.

<Applicable to Rated Voltage of less than 100VDC>

1-1. The load should be contained to the level such that when measuring at atmospheric temperature of 25°C, the product's self-heating remains below 20°C and the surface temperature of the capacitor in the actual circuit remains within the maximum operating temperature. [Example of Temperature Rise (Heat Generation) in Chip Monolithic Ceramic Capacitors in Contrast to Ripple Current]

Sample: R1 characteristics 10µF, Rated voltage: DC10V



5. DC Voltage and AC Voltage Characteristic

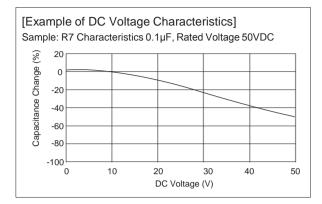
- The capacitance value of a high dielectric constant type capacitor changes depending on the DC voltage applied. Please consider the DC voltage characteristics when a capacitor is selected for use in a DC circuit.
- 1-1. The capacitance of ceramic capacitors may change sharply depending on the applied voltage. (See figure) Please confirm the following in order to secure the capacitance.
- (1) Determine whether the capacitance change caused by the applied voltage is within the allowed range .
- (2) In the DC voltage characteristics, the rate of capacitance change becomes larger as voltage increases, even if the applied voltage is below the rated voltage. When a high dielectric constant type capacitor is used in a circuit that requires a tight (narrow) capacitance tolerance (e.g., a time constant circuit), please carefully consider the voltage characteristics, and confirm the various characteristics in actual operating conditions in an actual system.
- The capacitance values of high dielectric constant type capacitors changes depending on the AC voltage applied.
 Please consider the AC voltage characteristics when selecting a capacitor to be used in a AC circuit.

6. Capacitance Aging

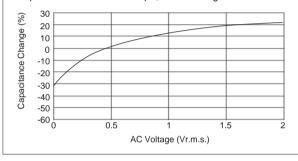
 The high dielectric constant type capacitors have the characteristic in which the capacitance value decreases with the passage of time.
 When you use a high dielectric constant type capacitors in a circuit that needs a tight (narrow) capacitance tolerance (e.g., a time-constant circuit), please carefully consider the characteristics of these capacitors, such as their aging, voltage, and temperature characteristics. In addition, check capacitors using your actual appliances at the intended environment and operating conditions.

7.Vibration and Shock

- 1. Please confirm the kind of vibration and/or shock, its condition, and any generation of resonance. Please mount the capacitor so as not to generate resonance, and do not allow any impact on the terminals.
- Mechanical shock due to being dropped may cause damage or a crack in the dielectric material of the capacitor. Do not use a fallen capacitor because the quality and reliability may be deteriorated.
- 3. When printed circuit boards are piled up or handled, the corner of another printed circuit board should not be allowed to hit the capacitor in order to avoid a crack or other damage to the capacitor.

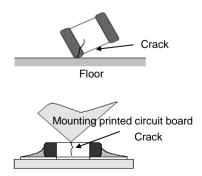






[Example of Change Over Time (Aging characteristics)]

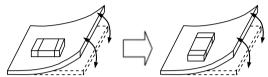




■Soldering and Mounting

1.Mounting Position

- 1. Confirm the best mounting position and direction that minimizes the stress imposed on the capacitor during flexing or bending the printed circuit board.
- 1-1.Choose a mounting position that minimizes the stress imposed on the chip during flexing or bending of the board. [Component Direction]



Locate chip horizontal to the direction in which stress acts.

[Chip Mounting Close to Board Separation Point]

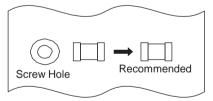
It is effective to implement the following measures, to reduce stress in separating the board. It is best to implement all of the following three measures; however, implement as many measures as possible to reduce stress.

Contents of Measures	Stress Level
(1) Turn the mounting direction of the component parallel to the board separation surface.	A > D
(2) Add slits in the board separation part.	A > B
(3) Keep the mounting position of the component away from the board separation surface.	A > C



[Mounting Capacitors Near Screw Holes]

When a capacitor is mounted near a screw hole, it may be affected by the board deflection that occurs during the tightening of the screw. Mount the capacitor in a position as far away from the screw holes as possible.

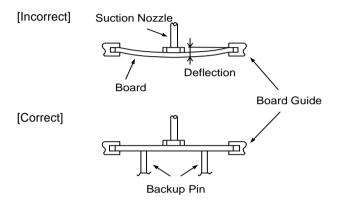


2.Information before Mounting

- 1. Do not re-use capacitors that were removed from the equipment.
- 2. Confirm capacitance characteristics under actual applied voltage.
- 3. Confirm the mechanical stress under actual process and equipment use.
- 4. Confirm the rated capacitance, rated voltage and other electrical characteristics before assembly.
- 5. Prior to use, confirm the solderability for the capacitors that were in long-term storage.
- 6. Prior to measuring capacitance, carry out a heat treatment for capacitors that were in long-term storage.
- 7. The use of Sn-Zn based solder will deteriorate the reliability of the MLCC. Please contact our sales representative or product engineers on the use of Sn-Zn based solder in advance.

3.Maintenance of the Mounting (pick and place) Machine

- 1. Make sure that the following excessive forces are not applied to the capacitors.
- 1-1. In mounting the capacitors on the printed circuit board, any bending force against them shall be kept to prevent them from any bending damage or cracking. Please take into account the following precautions and recommendations for use in your process.
 - (1) Adjust the lowest position of the pickup nozzle so as not to bend the printed circuit board.
 - (2) Adjust the nozzle pressure within a static load of 1N to 3N during mounting.



2.Dirt particles and dust accumulated between the suction nozzle and the cylinder inner wall prevent the nozzle from moving smoothly. This imposes greater force upon the chip during mounting, causing cracked chips. Also, the locating claw, when worn out, imposes uneven forces on the chip when positioning, causing cracked chips. The suction nozzle and the locating claw must be maintained, checked and replaced periodically.

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4-1.Reflow Soldering

- 1. When sudden heat is applied to the components, the mechanical strength of the components will decrease because a sudden temperature change causes deformation inside the components. In order to prevent mechanical damage to the components, preheating is required for both the components and the PCB. Preheating conditions are shown in table 1. It is required to keep the temperature differential between the solder and the components surface (Δ T) as small as possible.
- Solderability of tin plating termination chips might be deteriorated when a low temperature soldering profile where the peak solder temperature is below the melting point of tin is used. Please confirm the solderability of tin plated termination chips before use.
- 3. When components are immersed in solvent after mounting, be sure to maintain the temperature difference (Δ T) between the component and the solvent within the range shown in the table 1.

lable 1	
Part Number	Temperature Differential
GC□03/15/18/21/31	ΔT≦190°C
GC□32	ΔT≦130°C

Recommended Conditions

	Pb-Sn	Lead Free Solder	
	Reflow	Lead Tree Soluer	
Peak Temperature	230 to 250°C	230 to 240°C	240 to 260°C
Atmosphere	Air	Saturated vapor of inactive solvent	Air or N_2

Pb-Sn Solder: Sn-37Pb

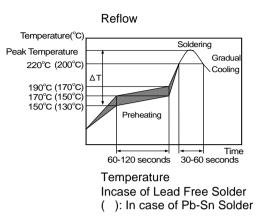
Lead Free Solder: Sn-3.0Ag-0.5Cu

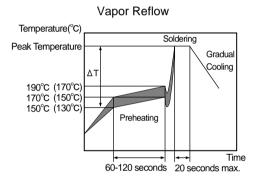
4. Optimum Solder Amount for Reflow Soldering

- 4-1. Overly thick application of solder paste results in a excessive solder fillet height. This makes the chip more susceptible to mechanical and thermal stress on the board and may cause
- the chips to crack.4-2. Too little solder paste results in a lack of adhesive strength on the outer electrode, which may result in
- chips breaking loose from the PCB.4-3. Make sure the solder has been applied smoothly to the end surface to a height of 0.2mm* min.

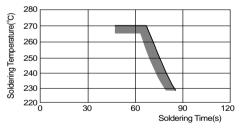
Inverting the PCB

Make sure not to impose any abnormal mechanical shocks to the PCB.

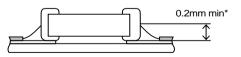




[Allowable Reflow Soldering Temperature and Time]



In the case of repeated soldering, the accumulated soldering time must be within the range shown above.



*GC□03: 1/3 of Chip Thickness min.

in section

4-2.Flow Soldering

1. Do not apply flow soldering to chips not listed in Table 2.

Table 2	
Part Number	Temperature Differential
GC□18/21/31 (Except for Temperature Characteristics:0C,5G,R9,L8)	ΔT≦150°C

- 2. When sudden heat is applied to the components, the mechanical strength of the components will decrease because a sudden temperature change causes deformation inside the components. In order to prevent mechanical damage to the components, preheating is required for both of the components and the PCB. Preheating conditions are shown in table 2. It is required to keep the temperature differential between the solder and the components surface (ΔT) as low as possible.
- 3. Excessively long soldering time or high soldering temperature can result in leaching of the outer electrodes, causing poor adhesion or a reduction in capacitance value due to loss of contact between the electrodes and end termination.
- 4. When components are immersed in solvent after mounting. be sure to maintain the temperature differential (ΔT) between the component and solvent within the range shown in the table 2.

Recommended Conditions

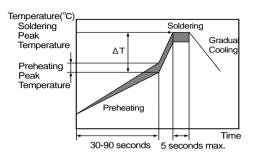
	Pb-Sn Solder	Lead Free Solder
Preheating Peak Temperature	90 to 110°C	100 to 120°C
Soldering Peak Temperature	240 to 250°C	250 to 260°C
Atmosphere	Air	Air

Pb-Sn Solder: Sn-37Pb

Lead Free Solder: Sn-3.0Ag-0.5Cu

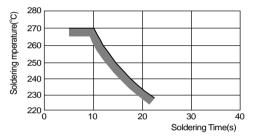
5. Optimum Solder Amount for Flow Soldering

5-1. The top of the solder fillet should be lower than the thickness of components. If the solder amount is excessive, the risk of cracking is higher during board bending or any other stressful condition.

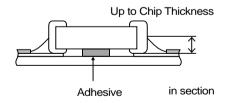


[Standard Conditions for Flow Soldering]

[Allowable Flow Soldering Temperature and Time]



In the case of repeated soldering, the accumulated soldering time must be within the range shown above.



4-3.Correction of Soldered Portion

When sudden heat is applied to the capacitor, distortion caused by the large temperature difference occurs internally, and can be the cause of cracks. Capacitors also tend to be affected by mechanical and thermal stress depending on the board preheating temperature or the soldering fillet shape, and can be the cause of cracks. Please refer to "1. PCB Design" or "3. Optimum solder amount" for the solder amount and the fillet shapes.

1. Correction with a Soldering Iron

- 1-1. In order to reduce damage to the capacitor, be sure to preheat the capacitor and the mounting board.
- Preheat to the temperature range shown in Table 3. A hot plate, hot air type preheater, etc. can be used for preheating. 1-2. After soldering, do not allow the component/PCB to cool down rapidly.
- 1-3. Perform the corrections with a soldering iron as quickly as possible. If the soldering iron is applied too long, there is a possibility of causing solder leaching on the terminal electrodes, which will cause deterioration of the adhesive strength and other problems.

Та	hle	З
ıa	nie	3

Part Number	Temperature of Soldering Iron tip	Preheating Temperature	Temperature Differential(ΔT)	Atmosphere
GC□03/15/18/21/31	350°C max.	150°C min.	ΔT≦190°C	Air
GC□32	280°C max.	150°C min.	ΔT≦130°C	Air

*Applicable for both Pb-Sn and Lead Free Sold Pb-Sn Solder: Sn-37Pb Lead Free Solder: Sn-3.0Ag-0.5Cu

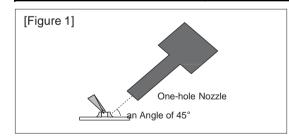
2. Correction with Spot Heater

Compared to local heating with a soldering iron, hot air heating by a spot heater heats the overall component and board, therefore, it tends to lessen the thermal shock. In the case of a high density mounted board, a spot heater can also prevent concerns of the soldering iron making direct contact with the component.

- 2-1. If the distance from the hot air outlet of the spot heater to the component is too close, cracks may occur due to thermal shock. To prevent this problem, follow the conditions shown in Table 4.
- 2-2. In order to create an appropriate solder fillet shape, it is recommended that hot air be applied at the angle shown in Figure 1.

(1210 (in inch) / 3225 (in mm) size or larger)

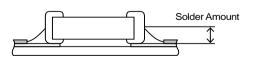
	Table 4		
Distance		5mm or more	
	Hot Air Application angle	45° *Figure 1	
	Hot Air Temperature Nozzle Outlet	400°C max.	
		Less than 10 seconds	
	Application Time	(1206 (in inch) / (3216 (in mm) size or smal	
		Less than 30 seconds	



- 3. Optimum solder amount when re-working with a soldering iron
- 3-1. In the case of 0603 (in inch) / 1608 (in mm) and smaller sizes (GC□03/15/18), the top of the solder fillet should be lower than 2/3 of the thickness of the component or 0.5mm, whichever is smaller.

In the case of 0805 (in inch) / 2012(in mm) and larger sizes (GC \Box 21/31/32), the top of the solder fillet should be lower than 2/3 of the thickness of the component. If the solder amount is excessive, the risk of cracking is higher during board bending or under any other stressful condition.

- 3-2. A soldering iron with a tip of ø3mm or smaller should be used. It is also necessary to keep the soldering iron from touching the components during the re-work.
- 3-3. Solder wire with Ø0.5mm or smaller is required for soldering.



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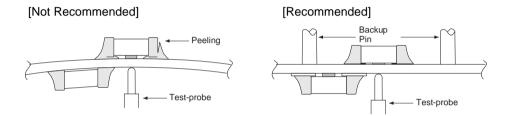
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5.Washing

Excessive ultrasonic oscillation during cleaning can cause the PCBs to resonate, resulting in cracked chips or broken solder joints. Take note not to vibrate PCBs.

6.Electrical Test on Printed Circuit Board

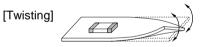
- 1. Confirm position of the backup pin or specific jig, when inspecting the electrical performance of a capacitor after mounting on the printed circuit board.
 - 1-1. Avoid bending the printed circuit board by the pressure of a test-probe, etc. The thrusting force of the test probe can flex the PCB, resulting in cracked chips or open solder joints. Provide backup pins on the back side of the PCB to prevent warping or flexing. Install backup pins as close to the test-probe as possible.
 - 1-2. Avoid vibration of the board by shock when a test -probe contacts a printed circuit board.



7.Printed Circuit Board Cropping

- 1. After mounting a capacitor on a printed circuit board, do not apply any stress to the capacitor that caused bending or twisting the board.
 - 1-1. In cropping the board, the stress as shown at right may cause the capacitor to crack. Cracked capacitors may cause deterioration of the insulation resistance, and result in a short. Avoid this type of stress to a capacitor.





2. Check the cropping method for the printed circuit board in advance.

2-1. Printed circuit board cropping shall be carried out by using a jig or an apparatus (Disk separator, router type separator, etc.) to prevent the mechanical stress that can occur to the board.

Board Separation Method	Hand Separation	(1) Board Separation Jig	Board Separation Apparatus	
	Nipper Separation		Disk Separator	3) Router Type Separator
Level of stress on board	High	Medium	Medium	Low
Recommended	×	Δ^*	Δ^*	\bigcirc
	Hand and nipper separation apply a high level of stress. Use another method.	 Board handling Board bending direction Layout of capacitors 	 Board handling Layout of slits Design of V groove Arrangement of blades Controlling blade life 	Board handling

* When a board separation jig or disk separator is used, if the following precautions are not observed, a large board deflection stress will occur and the capacitors may crack. Use router type separator if at all possible.

(1) Example of a suitable jig

[In the case of Single-side Mounting]

An outline of the board separation jig is shown as follows.

Recommended example: Stress on the component mounting position can be minimized by holding the portion close to the jig, and bend in the direction towards the side where the capacitors are mounted. Not recommended example: The risk of cracks occurring in the capacitors increases due to large stress being applied to the component mounting position, if the portion away from the jig is held and bent in the direction opposite the side where the capacitors are mounted.



[In the case of Double-sided Mounting]

Since components are mounted on both sides of the board, the risk of cracks occurring can not be avoided with the above method. Therefore, implement the following measures to prevent stress from being applied to the components. (Measures)

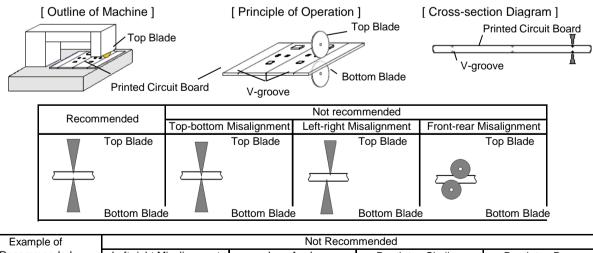
- (1) Consider introducing a router type separator.
 - If it is difficult to introduce a router type separator, implement the following measures. (Refer to item 1. Mounting Position)
- (2) Mount the components parallel to the board separation surface.
- (3) When mounting components near the board separation point, add slits in the separation position near the component.
- (4) Keep the mounting position of the components away from the board separation point.

(2) Example of a Disk Separator

An outline of a disk separator is shown as follows. As shown in the Principle of Operation, the top blade and bottom blade are aligned with the V-grooves on the printed circuit board to separate the board. In the following case, board deflection stress will be applied and cause cracks in the capacitors.

- (1) When the adjustment of the top and bottom blades are misaligned, such as deviating in the top-bottom, left-right or front-rear directions
- (2) The angle of the V groove is too low, depth of the V groove is too shallow, or the V groove is misaligned top-bottom

IF V groove is too deep, it is possible to brake when you handle and carry it. Carefully design depth of the V groove with consideration about strength of material of the printed circuit board.



Example of Not Recommended					
	Recommended	Left-right Misalignment	Low-Angle	Depth too Shallow	Depth too Deep

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(3) Example of Router Type Separator

The router type separator performs cutting by a router rotating at a high speed. Since the board does not bend in the cutting process, stress on the board can be suppressed during board separation. When attaching or removing boards to/from the router type separator, carefully handle the boards to prevent bending.

8. Assembly

1. Handling

If a board mounted with capacitors is held with one hand, the board may bend.

Firmly hold the edges of the board with both hands when handling.

If a board mounted with capacitors is dropped, cracks may occur in the capacitors.

Do not use dropped boards, as there is a possibility that the quality of the capacitors may be impaired.

2. Attachment of Other Components

2-1. Mounting of Other Components

Pay attention to the following items, when mounting other components on the back side of the board after capacitors have been mounted on the opposite side.

When the bottom dead point of the suction nozzle is set too low, board deflection stress may be applied to the capacitors on the back side (bottom side), and cracks may occur in the capacitors.

· After the board is straightened, set the bottom dead point of the nozzle on the upper surface of the board.

· Periodically check and adjust the bottom dead point.



2-2. Inserting Components with Leads into Boards

When inserting components (transformers, IC, etc.) into boards, bending the board may cause cracks in the capacitors or cracks in the solder. Pay attention to the following.

- · Increase the size of the holes to insert the leads, to reduce the stress on the board during insertion.
- \cdot Fix the board with backup pins or a dedicated jig before insertion.
- Support below the board so that the board does not bend. When using multiple backup pins on the board, periodically confirm that there is no difference in the height of each backup pin.

Component with Leads



2-3. Attaching/Removing Sockets

When the board itself is a connector, the board may bend when a socket is attached or removed. Plan the work so that the board does not bend when a socket is attached or removed.

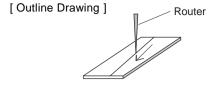


2-4. Tightening Screws

The board may be bent, when tightening screws, etc. during the attachment of the board to a shield or chassis. Pay attention to the following items before performing the work.

- · Plan the work to prevent the board from bending.
- · Use a torque screwdriver, to prevent over-tightening of the screws.
- The board may bend after mounting by reflow soldering, etc. Please note, as stress may be applied to the chips by forcibly flattening the board when tightening the screws.





Others

1. Under Operation of Equipment

- 1-1. Do not touch a capacitor directly with bare hands during operation in order to avoid the danger of an electric shock.
- 1-2. Do not allow the terminals of a capacitor to come in contact with any conductive objects (short-circuit). Do not expose a capacitor to a conductive liquid, inducing any acid or alkali solutions.
- 1-3. Confirm the environment in which the equipment will operate is under the specified conditions.
 - Do not use the equipment under the following environments.
 - (1) Being spattered with water or oil.
 - (2) Being exposed to direct sunlight.
 - (3) Being exposed to ozone, ultraviolet rays, or radiation.
 - (4) Being exposed to toxic gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)
 - (5) Any vibrations or mechanical shocks exceeding the specified limits.
 - (6) Moisture condensing environments.
- 1-4. Use damp proof countermeasures if using under any conditions that can cause condensation.

2. Others

- 2-1. In an Emergency
- (1) If the equipment should generate smoke, fire, or smell, immediately turn off or unplug the equipment. If the equipment is not turned off or unplugged, the hazards may be worsened by supplying continuous power.
- (2) In this type of situation, do not allow face and hands to come in contact with the capacitor or burns may be caused by the capacitor's high temperature.
- 2-2. Disposal of waste

When capacitors are disposed of, they must be burned or buried by an industrial waste vendor with the appropriate licenses.

- 2-3. Circuit Design
- (1) Addition of Fail Safe Function

Capacitors that are cracked by dropping or bending of the board may cause deterioration of the insulation resistance, and result in a short. If the circuit being used may cause an electrical shock, smoke or fire when a capacitor is shorted, be sure to install fail-safe functions, such as a fuse, to prevent secondary accidents.

(2) The GC series are not safety standard certified products.

2-4. Remarks

Failure to follow the cautions may result, worst case, in a short circuit and smoking when the product is used. The above notices are for standard applications and conditions. Contact us when the products are used in special mounting conditions.

Select optimum conditions for operation as they determine the reliability of the product after assembly. The data herein are given in typical values, not guaranteed ratings.

muRata Notice

Rating

1.Operating Temperature

- 1. The operating temperature limit depends on the capacitor.
- 1-1. Do not apply temperatures exceeding the upper operating temperature.
 It is necessary to select a capacitor with a suitable rated temperature that will cover the operating temperature range.
 It is also necessary to consider the temperature distribution in equipment and the seasonal temperature variable factor.
- 1-2. Consider the self-heating factor of the capacitor The surface temperature of the capacitor shall be the upper operating temperature or less when including the self-heating factors.

2.Atmosphere Surroundings (gaseous and liquid)

- 1. Restriction on the operating environment of capacitors.
- 1-1. Capacitors, when used in the above, unsuitable, operating environments may deteriorate due to the corrosion of the terminations and the penetration of moisture into the capacitor.
- 1-2. The same phenomenon as the above may occur when the electrodes or terminals of the capacitor are subject to moisture condensation.
- 1-3. The deterioration of characteristics and insulation resistance due to the oxidization or corrosion of terminal electrodes may result in breakdown when the capacitor is exposed to corrosive or volatile gases or solvents for long periods of time.

3.Piezo-electric Phenomenon

1. When using high dielectric constant type capacitors in AC or pulse circuits, the capacitor itself vibrates at specific frequencies and noise may be generated. Moreover, when the mechanical vibration or shock is added to capacitor, noise may occur.

■Soldering and Mounting

1.PCB Design

Pattern Forme

- 1. Notice for Pattern Forms
- 1-1. Unlike leaded components, chip components are susceptible to flexing stresses since they are mounted directly on the substrate.
 They are also more sensitive to mechanical and thermal stresses than leaded components.
 Excess solder fillet height can multiply these stresses and cause chip cracking.
 When designing substrates, take land patterns and dimensions into consideration to eliminate the possibility of excess solder fillet height.
- 1-2. There is a possibility of chip cracking caused by PCB expansion/contraction with heat, because stress on a chip is different depending on PCB material and structure. When the thermal expansion coefficient greatly differs between the board used for mounting and the chip, it will cause cracking of the chip due to the thermal expansion and contraction. When capacitors are mounted on a fluorine resin printed circuit board or on a single-layered glass epoxy board, it may also cause cracking of the chip for the same reason.

	Prohibited	Correct
Placing Close to Chassis	Chassis Solder (ground) Electrode Pattern in section	Solder Resist
Placing of Chip Components and Leaded Components	Lead Wire	Solder Resist
Placing of Leaded Components after Chip Component	Soldering Iron Lead Wire	Solder Resist in section
Lateral Mounting		Solder Resist

Notice

2. Land Dimensions

2-1. Chip capacitors can be cracked due to the stress of PCB bending , etc. if the land area is larger than needed and has an excess amount of solder. Please refer to the land dimensions in table 1 for flow soldering, table 2 for reflow soldering.

Please confirm the suitable land dimension by evaluating of the actual SET / PCB.



Table 1 Flow Soldering Method

Dimensions Part Number	L×W	а	b	С
GC□18	1.6×0.8	0.6 to 1.0	0.8 to 0.9	0.6 to 0.8
GC□21	2.0×1.25	1.0 to 1.2	0.9 to 1.0	0.8 to 1.1
GC□31	3.2×1.6	2.2 to 2.6	1.0 to 1.1	1.0 to 1.4

Flow soldering can only be used for products with a chip size of 1.6x0.8mm to 3.2x1.6mm. (in mm)

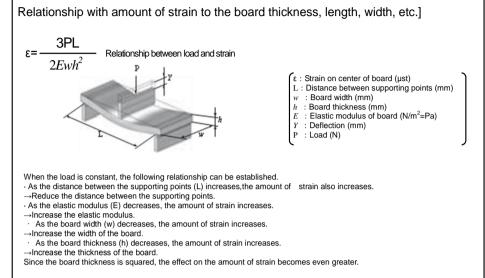
Table 2 Reflow Soldering Method

Dimensions Part Number	L×W	а	b	С
GC□03	0.6×0.3	0.2 to 0.3	0.2 to 0.35	0.2 to 0.4
GC□15	1.0×0.5	0.3 to 0.5	0.35 to 0.45	0.4 to 0.6
GC□18	1.6×0.8	0.6 to 0.8	0.6 to 0.7	0.6 to 0.8
GC□21	2.0×1.25	1.0 to 1.2	0.6 to 0.7	0.8 to 1.1
GC□31	3.2×1.6	2.2 to 2.4	0.8 to 0.9	1.0 to 1.4
GC□32	3.2×2.5	2.0 to 2.4	1.0 to 1.2	1.8 to 2.3

(in mm)

3. Board Design

When designing the board, keep in mind that the amount of strain which occurs will increase depending on the size and material of the board.



2.Adhesive Application

 Thin or insufficient adhesive can cause the chips to loosen or become disconnected during flow soldering. The amount of adhesive must be more than dimension c, shown in the drawing at right, to obtain the correct bonding strength. The chip's electrode thickness and land thickness must also be taken into consideration.



- Low viscosity adhesive can cause chips to slip after mounting. The adhesive must have a viscosity of 5000Pa • s (500ps) min. (at 25°C)
- 3. Adhesive Coverage

Size (L×W) (in mm)	Adhesive Coverage*	
1.6 × 0.8	0.05mg min.	
2.0 × 1.25	0.1mg min.	
3.2 × 1.6	0.15mg min.	
	*Nominal Value	

3.Adhesive Curing

 Insufficient curing of the adhesive can cause chips to disconnect during flow soldering and causes deterioration in the insulation resistance between the outer electrodes due to moisture absorption. Control curing temperature and time in order to prevent insufficient hardening.

<u>4.Flux</u>

- 1. An excessive amount of flux generates a large quantity of flux gas, which can cause a deterioration of solderability, so apply flux thinly and evenly throughout. (A foaming system is generally used for flow solderring.)
- 2. Flux containing too high a percentage of halide may cause corrosion of the outer electrodes unless there is sufficient cleaning. Use flux with a halide content of 0.1% max.
- 3. Do not use strong acidic flux.
- Do not use water-soluble flux.*
 (*Water-soluble flux can be defined as non-rosin type flux including wash-type flux and non-wash-type flux.)



5.Flow Soldering

Set temperature and time to ensure that leaching of the outer electrode does not exceed 25% of the chip end area as a single chip (full length of the edge A-B-C-D shown at right) and 25% of the length A-B shown as mounted on substrate.



6.Washing

- 1. Please evaluate the capacitor using actual cleaning equipment and conditions to confirm the quality, and select the solvent for cleaning.
- 2. Unsuitable cleaning solvent may leave residual flux or other foreign substances, causing deterioration of electrical characteristics and the reliability of the capacitors.
- 3. Select the proper cleaning conditions.
- 3-1. Improper cleaning conditions (excessive or insufficient) may result in the deterioration of the performance of the capacitors.

7.Coating

 A crack may be caused in the capacitor due to the stress of the thermal contraction of the resin during curing process. The stress is affected by the amount of resin and curing contraction. Select a resin with low curing contraction. The difference in the thermal expansion coefficient between a coating resin or a molding resin and the capacitor may cause the destruction and deterioration of the capacitor such as a crack or peeling, and lead to the deterioration of insulation resistance or dielectric breakdown.

Select a resin for which the thermal expansion coefficient is as close to that of the capacitor as possible. A silicone resin can be used as an under-coating to buffer against the stress.

2. Select a resin that is less hygroscopic.

Using hygroscopic resins under high humidity conditions may cause the deterioration of the insulation resistance of a capacitor. An epoxy resin can be used as a less hygroscopic resin.

Others

1.Transportation

1. The performance of a capacitor may be affected by the conditions during transportation.

- 1-1. The capacitors shall be protected against excessive temperature, humidity and mechanical force during transportation.
 - (1) Climatic condition
 - · low air temperature : -40°C
 - change of temperature air/air : -25°C/+25°C
 - · low air pressure : 30 kPa
 - · change of air pressure : 6 kPa/min.
 - (2) Mechanical condition
 - Transportation shall be done in such a way that the boxes are not deformed and forces are not directly passed on to the inner packaging.
- 1-2. Do not apply excessive vibration, shock, or pressure to the capacitor.
 - (1) When excessive mechanical shock or pressure is applied to a capacitor, chipping or cracking may occur in the ceramic body of the capacitor.
 - (2) When the sharp edge of an air driver, a soldering iron, tweezers, a chassis, etc. impacts strongly on the surface of the capacitor, the capacitor may crack and short-circuit.
- 1-3. Do not use a capacitor to which excessive shock was applied by dropping etc.
 - A capacitor dropped accidentally during processing may be damaged.

2. Characteristics Evaluation in the Actual System

- 1. Evaluate the capacitor in the actual system, to confirm that there is no problem with the performance and specification values in a finished product before using.
- 2. Since a voltage dependency and temperature dependency exists in the capacitance of high dielectric type ceramic capacitors, the capacitance may change depending on the operating conditions in the actual system. Therefore, be sure to evaluate the various characteristics, such as the leakage current and noise absorptivity, which will affect the capacitance value of the capacitor.
- 3. In addition, voltages exceeding the predetermined surge may be applied to the capacitor by the inductance in the actual system. Evaluate the surge resistance in the actual system as required.

- 1.Please make sure that your product has been evaluated in view of your specifications with our product being mounted to your product.
- 2. Your are requested not to use our product deviating from this product specification.
- 3.We consider it not appropriate to include any terms and conditions with regard to the business transaction in the product specifications, drawings or other technical documents. Therefore, if your technical documents as above include such terms and conditions such as warranty clause, product liability clause, or intellectual property infringement liability clause, they will be deemed to be invalid.

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